Search Notes					

Application/Control No. Applicant(s)/Patent under Reexamination	
10/688,294	CHEN ET AL.
Examiner	Art Unit
Pia F. Tibbits	2838

SEARCHED				
Class	Subclass	Date	Examiner	
320	106	10/6/2005	PT	
	132			
455	404.1			
704	272			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEAR (INCLUDING S	CH NOTES EARCH STRATEC	SY)
	DATE	EXMR
east	10/6/2005	5 PT
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